



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Wayne A. Weimer § Docket No.: 34003.30
Serial No.: 09/852,992 § Examiner: Timothy H. Meeks
Filed: May 10, 2001 § Art Unit: 1762
Entitled: System and Method for Controlling §
Deposition Parameters in Producing §
a Surface to Tune the Surface's §
Plasmon Resonance Wavelength §

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner For Patents
P.O. Box 1450
Alexandria, VA 22313-1450

In compliance with the duty of disclosure under 37 CFR §1.56, and in accordance with the practice under 37 CFR §1.97 and §1.98, the Examiner's attention is directed to the documents listed on the enclosed modified Form PTO-1449. No inference should be made that the cited references are in fact material, are in fact prior art, or that no better art exists. The cited patents are listed in numerical and alphabetical order and are not in any order based on their pertinence.

This Supplemental Information Disclosure Statement is being filed within three months of the United States filing date or before the mailing date of a first Office Action on the merits. No certification or fee is required (37 CFR §1.97(b)).

Applicant believes no fee is due. However, the Commissioner is hereby authorized to charge any deficiency fees or credit any overpayments associated with this communication to Deposit Account 08-1394 of Haynes and Boone, LLP.

It is respectfully requested that the above information be considered by the Examiner and that a copy of the enclosed Form PTO-1449 be returned indicating that such information has been considered.

Respectfully submitted,

Randall C. Brown
Registration No. 31,213

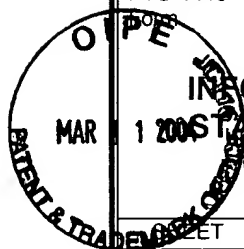
Date: 3/8/04

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Certificate of Mailing

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to Commissioner For Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on the date indicated below.

Ellen Lovelace
Name
March 8, 2004
Date



In place of PTO-1449	U. S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)		Application Number	09/852,992
		Filing Date	May 10, 2001
		Applicant(s)	Wayne A. Weimer
		Art Unit	1762
		Examiner Name	Timothy H. Meeks
Page 1 of 1	1 OF 1	Attorney Docket Number	34003.30

U. S. PATENT DOCUMENTS				
Examiner's Initials	Cite No.	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
	AA	6,608,716	08-19-2003	Armstrong, et al.

FOREIGN PATENT DOCUMENTS					
Examiner's Initials	Cite No.	Foreign Patent Document (Country Code - Number - Kind)	Publication Date MM-DD-YYYY	Patentee or Applicant of Cited Document	Translation Y/N

OTHER PRIOR ART		
Examiner's Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article, title of the item, date, page(s), volume-issue number(s), publisher, city/country where published
	AB	Kim, W., et al., "Fractals in Microcavities: Giant Coupled, Multiplicative Enhancement of Optical Responses", Physical Review Letters, Vol. 82, Issue 24, June 14, 1999, pp. 4811-4814.
	AC	Kneipp, Katrin, et al., "Single Molecule Detection Using Surface-Enhanced Raman Scattering (SERS)", Physical Review Letters, Vol. 78, Number 9, March 3, 1997, pp. 1667-1670.
	AD	Nie, Shuming, et al., "Probing Single Molecules and Single Nanoparticles by Surface-Enhanced Raman Scattering", Science, Vol. 275, February 21, 1997, pp. 1102-1106.

Examiner Signature		Date Considered	
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include a copy of this form with next communication to applicant.